

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BECKMANN ET AL.	
		Examiner Tony Chuo	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0025460	02-2002	Horiguchi et al.	429/13
*	B	US-2002/0016684	02-2002	Bruckner, Dieter	702/22
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04-274174	09-1992	Japan	Tanizaki et al	H01M8/24
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	P					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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